DOCUMENT CHANGE REQUEST

DCR number 1301

Changes required for: General

Originator: Steve Thacker

Date: 2019/12/13

Date sent: 2019/10/04

Organisation: ESCC Executive Secretariat

Status: IMPLEMENTED

Title:	Transistors High Voltage NPN, based on type 2N5551		
Number:	5201/019	Issue:	7

Other documents affected:

Page:

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Paragraph:

Appendix A - AGREED DEVIATIONS FOR STMICROELECTRONICS (F)

Original wording:

See 5201/019 issue 7

Proposed wording:

In Appendix A (for ST), item Para 2.4.1, amend as follows:

Add the following (after A summary ... Order):
Characteristic hfe1 (Small-Signal Short-Circuit Forward-Current Transfer Ratio) shall be omitted.

For consistency purposes also amend the following in Appendix A item Para 2.4.1:
In the table for hfe2 (High Frequency Small-Signal Short-Circuit Forward-Current Transfer Ratio):
Amend characteristic name to be Small-Signal Short-Circuit Forward-Current Transfer Ratio and the MIL-STD-750 test method to be 3206 (was 3306).

Justification:

This DCR is raised on behalf of ESCCQPL listed Manufacturer: ST.

As stated by ST, this DCR is raised in order to harmonize the test programs for ESCC and for the equivalent MIL JAN type (2N5551). The goal is to get one test program for the two systems.
This hfe1 test is to be deleted from the ESCC spec as it isnt required in the MIL spec.
ref. specs:
: ESCC spec for 2N5551: 5201/019 issue 7
: MIL spec for JANS2N5551, etc: MIL-PRF-19500/767C

Attachments:
N/A
Modifications:
N/A
Approval signature:
Date signed:
2019-12-13